

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
TEWES ET AL PCTSERIAL NO.
09/319,092

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT
MICHAEL TEWES ET ALFILING DATE
JUNE 18, 1999GROUP
2878

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,296,700	8/1994	Kumagai			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLAS S	SUBCLASS	TRANSLATION	
							YES	NO
	AL	0-731-371	03/1995	European appln.				
SL	AM	0 941 470	11/1997	European appln.				✓
SL	AN	WO 90/01716	08/1989	International				
	AO	WO 94/16313	01/1994	International				
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	✓	"Mikroskopgestuetzte-Fluoreszenz-Photonen-Korrelation"- by M. Völeker et al, <u>Technisches Messen</u> 63 (1996) Oldenbourg
SL	AS	✓	"Fluoreszenz-Korrelations-Spektrometer" April 1996, Carl Zeiss Jena GmbH

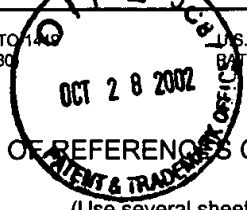
EXAMINER

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DATE CONSIDERED

1/5/03

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	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	✓	History of Leica Confocal Microscope System
SL	AS	✓	Fluorescence lifetime measurements using a novel fiber-optic laser.. REV. Sci Instrum 63(5) 2998-3002, May 1992 K.P. Ghiggino et al, University of Melbourne, Australia 4/22/92
	AT	✓	Improved fluorescence correlation apparatus for precise ... J. Schneider et al, University of Berne, Switzerland Dec. 4, 1987

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—	AR	✓	Dual-Color Fluorescence Cross-Correlation Spectroscopy for Multi-component ... P. Schwille et al Biophysical Journal Vol.72 Apr. 1997
—	AS	✓	Handbook of Biological Confocal Microscopy — D.R. Sandison et al — Plenum Press, New York, 1985
SL	AT	✓	Scanning Concentration Correlation Spectroscopy using ... D. E. Koppel et al, <i>Biophysical Journal</i> 66 p 562-567, February 1994 Univ. of Connecticut, Farmington, Conn. 1994

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	AP						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)			
51	✓ AR		Analysis of confocal laser-microscope optics for 3-D fluorescence...
			Hong Qian et al - Applied Optics, Apr. 1, 1991, vol. 30, No. 10 1185-1195
	✓ AS		Fluorescence-Correlation-Spectroscopy by N. Thompson
			Univ. of N.C. Chapel Hill, N.C. - Plenum Press, NY 1991
	AT		

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